

2SA1416 / 2SC3646

Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	
Collector Cutoff Current	I_{CBO}	$V_{CB}=(-)100V, I_E=0A$			$(-)100$	nA
Emitter Cutoff Current	I_{EBO}	$V_{EB}=(-)4V, I_C=0A$			$(-)100$	nA
DC Current Gain	h_{FE}	$V_{CE}=(-)5V, I_C=(-)100mA$	100*		400*	
Gain-Bandwidth Product	f_T	$V_{CE}=(-)10V, I_C=(-)100mA$		120		MHz
Output Capacitance	C_{ob}	$V_{CB}=(-)10V, f=1MHz$		(13)8.5		pF
Collector-to-Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C=(-)400mA, I_B=(-)40mA$		$(-0.2)0.1$	$(-0.6)0.4$	V
Base-to-Emitter Saturation Voltage	$V_{BE(sat)}$	$I_C=(-)400mA, I_B=(-)40mA$		$(-)0.85$	$(-)1.2$	V
Collector-to-Base Breakdown Voltage	$V_{(BR)CBO}$	$I_C=(-)10\mu A, I_E=0A$	$(-)120$			V
Collector-to-Emitter Breakdown Voltage	$V_{(BR)CEO}$	$I_C=(-)1mA, R_{BE}=\infty$	$(-)100$			V
Emitter-to-Base Breakdown Voltage	$V_{(BR)EBO}$	$I_E=(-)10\mu A, I_C=0A$	$(-)6$			V
Turn-ON Time	t_{on}	See specified Test Circuit.		(80)80		ns
Storage Time	t_{stg}	See specified Test Circuit.		(700)850		ns
Fall Time	t_f	See specified Test Circuit.		(40)50		ns

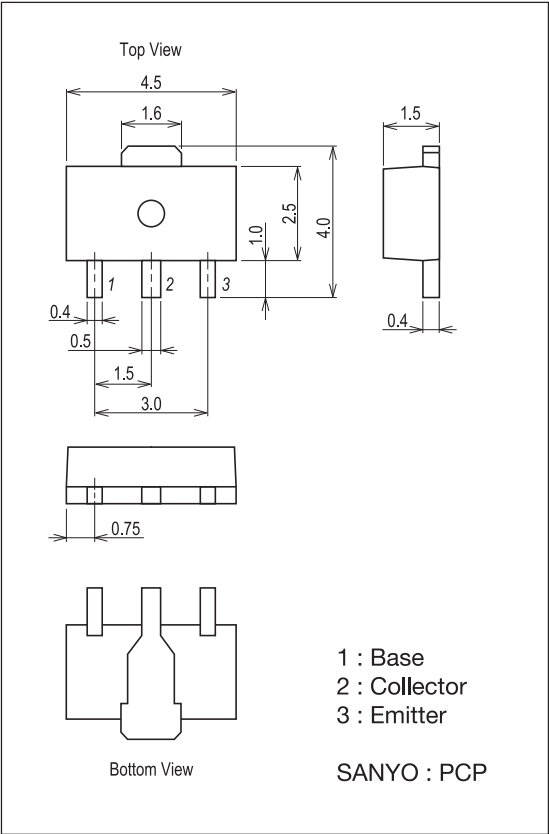
*: The 2SA1416 / 2SC3646 are classified by 100mA h_{FE} as follows:

Rank	R	S	T
h_{FE}	100 to 200	140 to 280	200 to 400

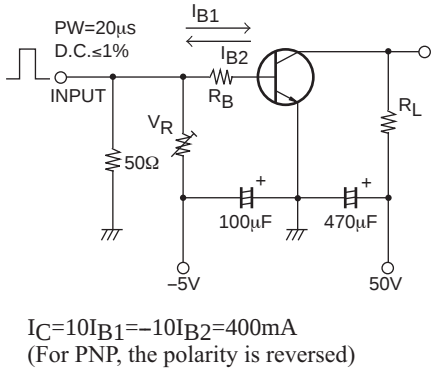
Package Dimensions

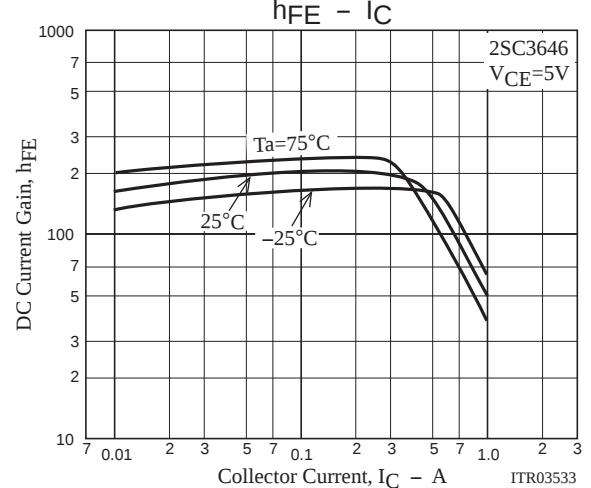
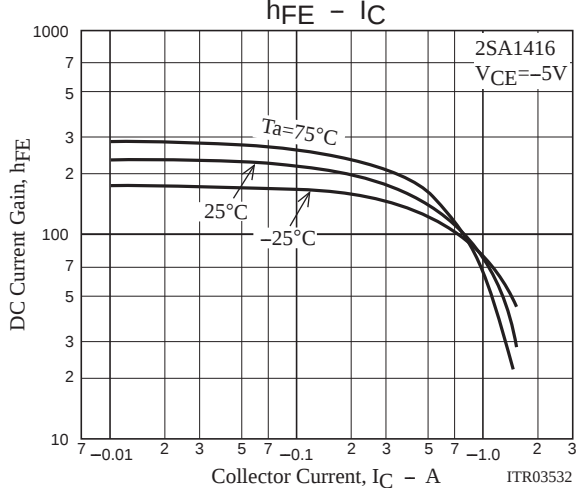
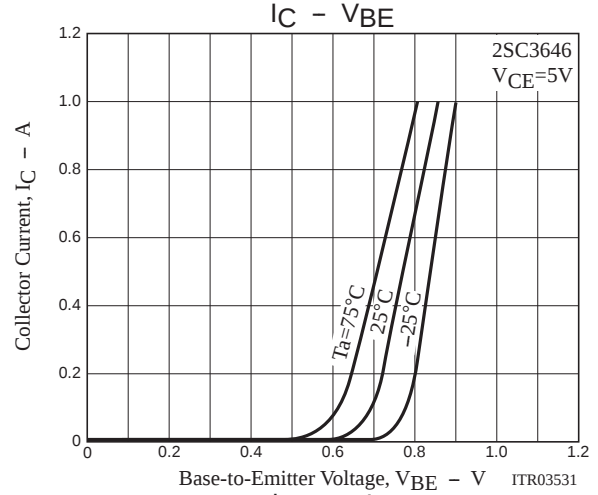
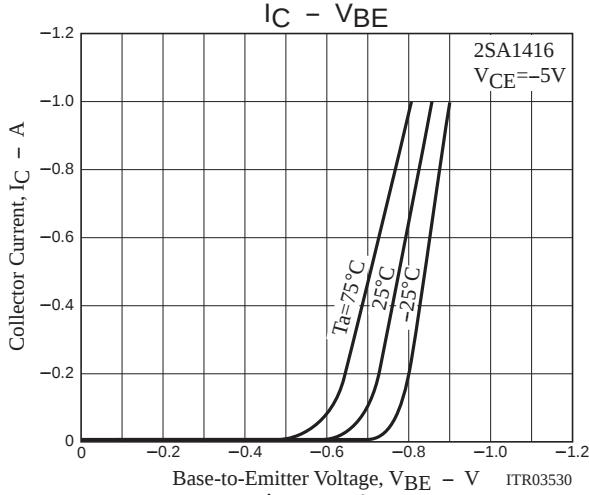
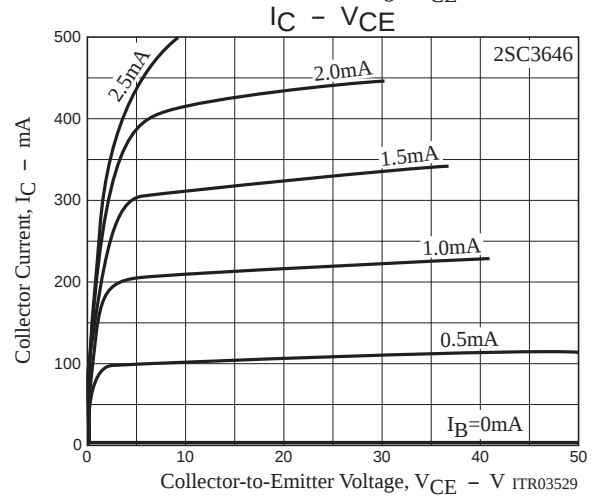
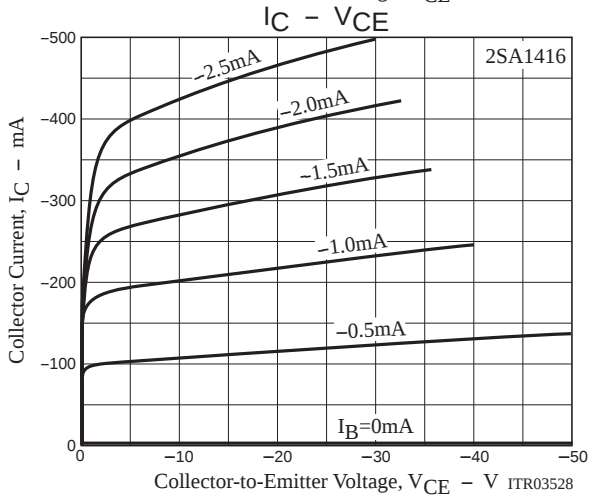
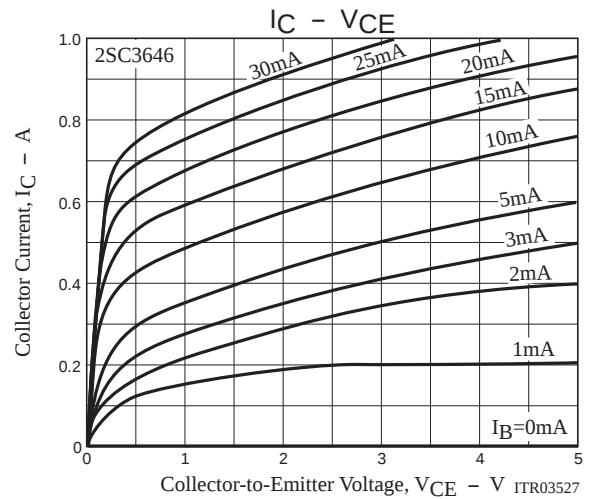
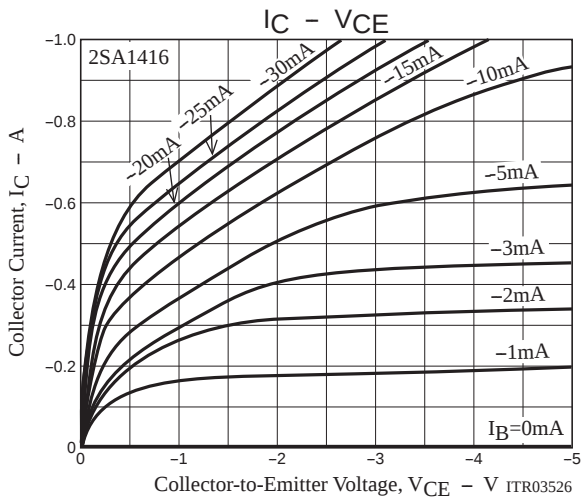
unit : mm (typ)

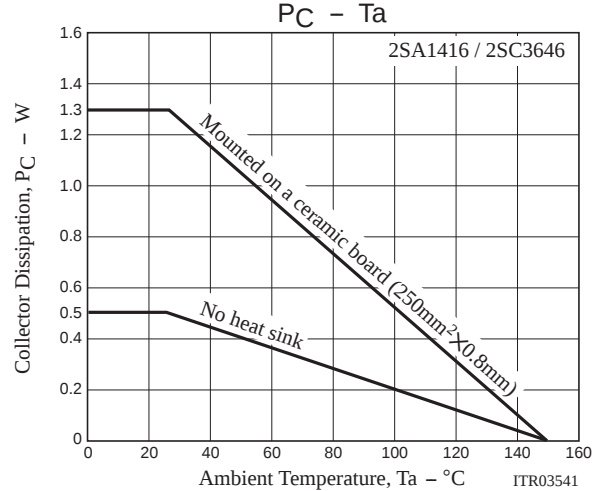
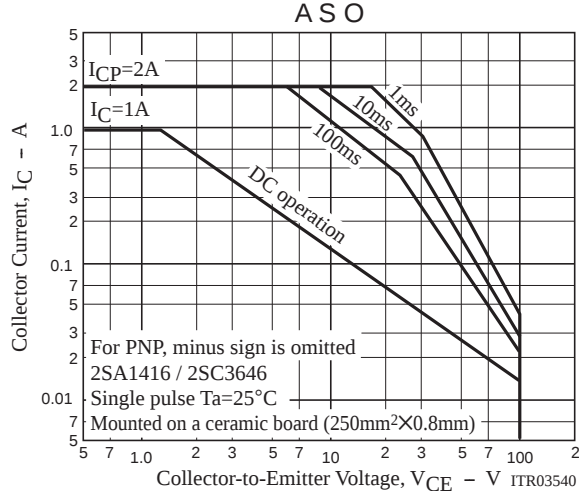
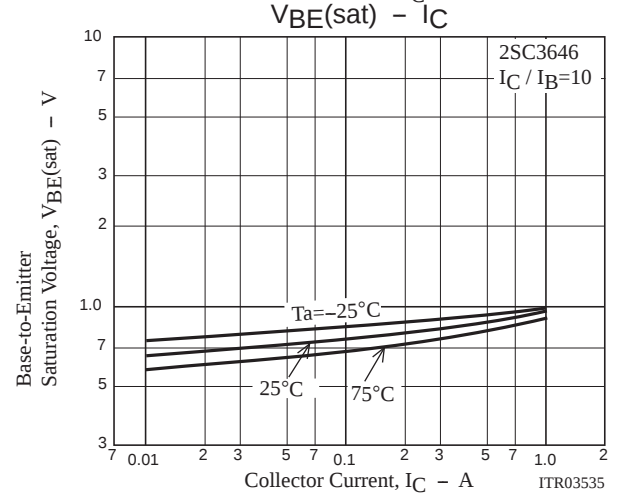
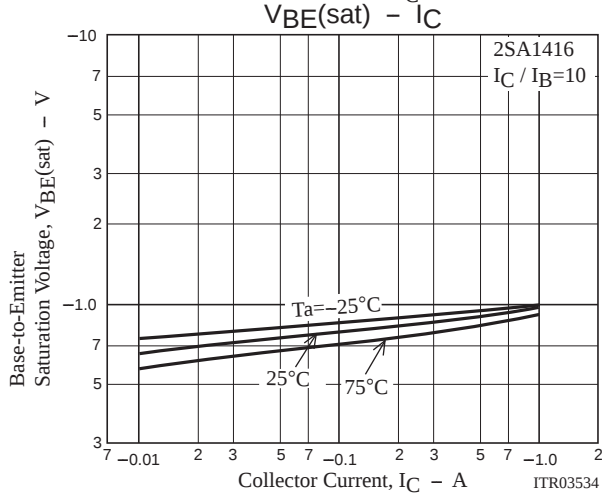
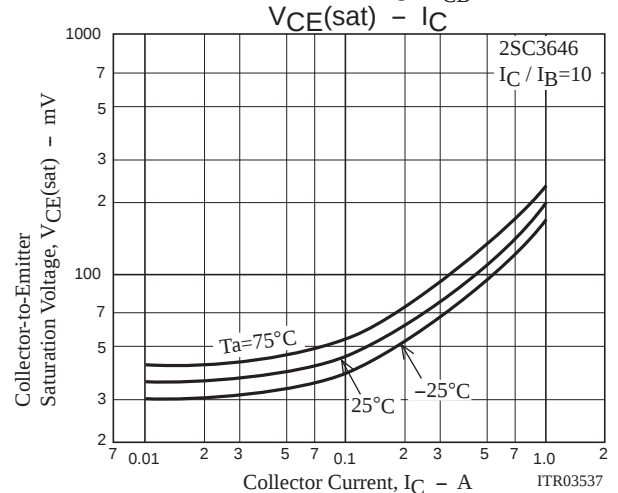
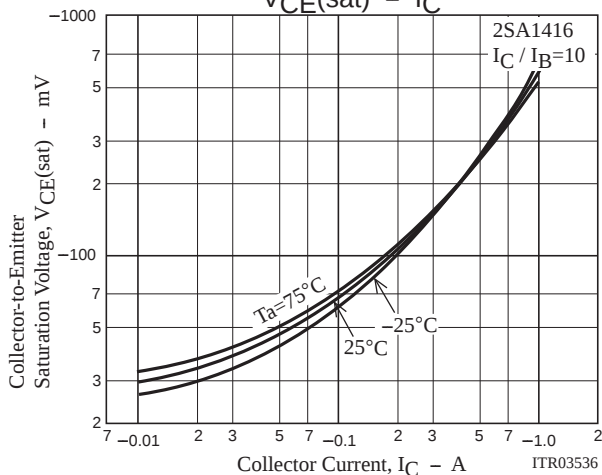
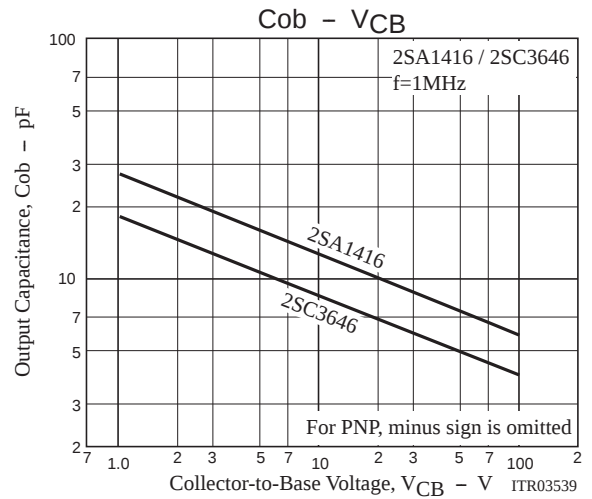
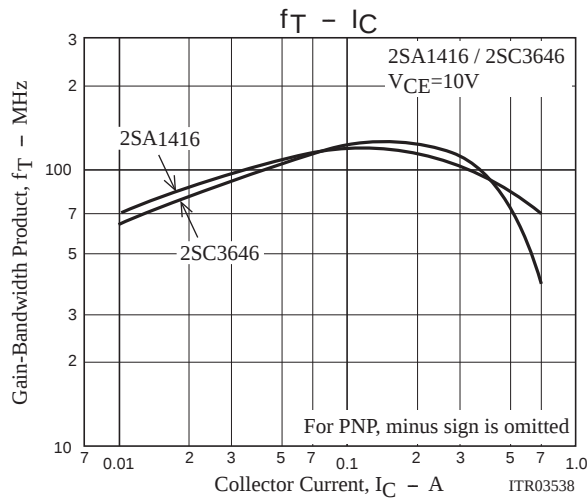
7007B-004



Switching Time Test Circuit







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